

(19) AUSTRALIAN PATENT OFFICE

(54) Title
Methods and apparatus for determining device integrity

(51)⁶ International Patent Classification(s)
H04B 17/00 (2006.01) 20060101AFI20060101
H04B 17/00 BHAU
PCT/US2004/027037

(21) Application No: **2004273429** (22) Application Date: **2004 .08 .17**

(87) WIPO No: **WO05/026877**

(30) Priority Data

(31) Number (32) Date (33) Country
10/659,847 2003 .09 .10 US

(43) Publication Date : **2005 .03 .24**

(71) Applicant(s)
Qualcomm Incorporated

(72) Inventor(s)
Mclean, Ivan Hugh

(74) Agent/Attorney
MADDERNS, 1st Floor 64 Hindmarsh Square, ADELAIDE, SA, 5000